

**Notice of References Cited**

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Applicant(s)/Patent Under  
Reexamination  
GREVE, MICHAEL

Examiner

HO SHIU

Art Unit

2457

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0116641 A1	08-2002	Mastrianni, Steven J.	713/201
*	B	US-6,654,787 B1	11-2003	Aronson et al.	709/206
*	C	US-2004/0210639 A1	10-2004	Ben-Yoseph et al.	709/206
*	D	US-2005/0080642 A1	04-2005	Daniell, W. Todd	705/001
*	E	US-2005/0080889 A1	04-2005	Malik et al.	709/223
*	F	US-2005/0080867 A1	04-2005	Malik et al.	709/207
*	G	US-2005/0080862 A1	04-2005	Kent et al.	709/206
*	H	US-2005/0080851 A1	04-2005	Kent et al.	709/205
*	I	US-2005/0097174 A1	05-2005	Daniell, W. Todd	709/206
*	J	US-2005/0160144 A1	07-2005	Bhatia, Rishi	709/206
*	K	US-6,941,466 B2	09-2005	Mastrianni, Steven J.	726/22
*	L	US-2005/0210116 A1	09-2005	Samson, Ronald W.	709/207
*	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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